

| | | | |
|-----------------------------------|---------------------------------------|--|-------------|
| Notice of References Cited | Application/Control No. 10/690,117 | Applicant(s)/Patent Under Reexamination YOSHIDA, MIINORU | |
| | Examiner Cheukfan Lee | Art Unit 2627 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|---------------------|----------------|
| * | A | US-6,128,105 | 10-2000 | Ishikawa et al. | 358/483 |
| * | B | US-6,154,294 | 11-2000 | Craig et al. | 358/483 |
| * | C | US-5,486,932 | 01-1996 | Leonard, Jacques V. | 358/498 |
| * | D | US-4,989,099 | 01-1991 | Koshiyouji et al. | 358/474 |
| * | E | US-5,781,311 | 07-1998 | Inoue et al. | 358/475 |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.